

<b>Notice of References Cited</b>	Application/Control No. 10/604,343	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Thien M. Le	Art Unit 2876	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,626,360	09-2003	Huang, Chih-Wen	235/454
	B	US-6,612,681	09-2003	Hasegawa et al.	347/22
	C	US-6,471,202	10-2002	Sugimura, Hideo	271/10.11
	D	US-6,382,858	05-2002	Nojima et al.	400/691
	E	US-6,318,836	11-2001	Hasegawa et al.	347/33
	F	US-6,305,608	10-2001	Nada et al.	235/472.03
	G	US-6,084,824	07-2000	Farr, Mina	365/234
	H	US-5,864,130	01-1999	Kahn et al.	235/462.01
	I	US-5,345,431	09-1994	Oliver et al.	369/13.18
	J	US-5,175,420	12-1992	Bianco, James S.	235/462.33
	K	US-4,609,818	09-1986	Lenne mann et al.	250/234
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.